

INTERNATIONAL STANDARD

**Integrated circuits – EMC evaluation of transceivers –
Part 1: General conditions and definitions**

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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**INTEGRATED CIRCUITS –
EMC evaluation of transceivers –**

Part 1: General conditions and definitions

FOREWORD

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International Standard IEC 62228-1 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this International Standard is based on the following documents:

CDV	Report on voting
47A/1018/CDV	47A/1034/RVC

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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